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Attorney

41,733 Reg. No.

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of:

Applicant

James W. Siekkinen et al.

Serial No.

09/833,174

Filed

April 11, 2001 CURRENT ACTUATED SWITCH

Title Docket No.

015559-238

Art Unit

2816

Commissioner for Patents Washington, D.C. 20231

INFORMATION DISCLOSURE STATEMENT

Pursuant to 37 C.F.R. §1.56, the Examiner's attention is directed to the references listed on the attached Information Disclosure Citation, copies of which are attached.

It is to be understood that the present submission of art is in no way intended to be a waiver of any arguments or defenses available to the applicant under the rules of the U.S. Patent and Trademark Office and the statutes of the United States.

No fee is required. The Commissioner is authorized to charge any additional fees required by this paper or to credit any overpayment to Deposit Account No. 20-0809.

Respectfully submitted:

By: __

Steven J. Elleman

Reg. No. 41,733

Serial No.: 09/833,174 Docket No.: 015559-238

Information Disclosure Statement

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INFORMATION DISCLOSURE CITATION

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Docket:	015559-238	Serial. No.: 09/833,174

Applicant: James W. Siekkinen et al.

Filed: 4/11/01 Group: 2816

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